

**Manufacturers Suggested International Retail Price  
NT-MDT SPM accessories, January 2012  
(Cantilevers, Test samples, HOPG, SNOM probes)**

**NEW!!! Top Visual Non-contact silicon AFM probes - VIT\_P series**  
each chip has 1 rectangular lever with inclined tip,  
typical curvature radius is 6 nm, no reflective coating  
resonant frequency 300 kHz / force constant 50 N/m

P/N	ITEM	PRICE, Euro
VIT_P/50	50 separated chips	1190
VIT_P/25	25 separated chips	666
VIT_P/15	15 separated chips	405

**High Accuracy ETALON probes - HA\_NC series,**  
each chip has 2 rectangular polysilicon levers with sharp silicon tip (typical 10nm),  
Au reflective coating,  
resonant frequency 120/200 kHz / force constant 3.4 / 5.8N/m with typical dispersion ± 20%.

P/N	ITEM	PRICE, Euro
HA_NC/400	400 separated chips	3120
HA_NC/300	300 separated chips	2790
HA_NC/200	200 separated chips	2250
HA_NC/100	100 separated chips	1200
HA_NC/50	50 separated chips	750
HA_NC/15	15 separated chips	260

**NONCONTACT "Golden" silicon cantilevers - NSG01, NSG10, NSG03, NSG30 series,**  
each chip has 1 rectangular lever,  
typical curvature radius is 6 nm, Au reflective coating \*

P/N	ITEM	PRICE, Euro
NSG01W, NSG10W, NSG03W, NSG30W	Nonseparated wafer, minimum 410 chips	4080
NSG01/400, NSG10/400, NSG03/400, NSG30/400	400 separated chips	4420
NSG01/300, NSG10/300, NSG03/300, NSG30/300	300 separated chips	3570
NSG01/200, NSG10/200, NSG03/200, NSG30/200	200 separated chips	2550
NSG01/100, NSG10/100, NSG03/100, NSG30/100	100 separated chips	1360
NSG01/50, NSG10/50, NSG03/50, NSG30/50	50 separated chips	850
NSG01/15, NSG10/15, NSG03/15, NSG30/15	15 separated chips	300

**Force Modulation "Golden" silicon cantilevers - FMG01 series,**  
each chip includes 1 rectangular spring,  
typical curvature radius is 6 nm, Au reflective coating \*  
typical resonant frequency is 60kHz, typical force constant is 3N/m:

P/N	ITEM	PRICE, Euro
FMG01W	Nonseparated wafer, minimum 410 chips	4080
FMG01/400	400 separated chips	4420
FMG01/300	300 separated chips	3570
FMG01/200	200 separated chips	2550
FMG01/100	100 separated chips	1360
FMG01/50	50 separated chips	850
FMG01/15	15 separated chips	300

**CONTACT "Golden" silicon cantilevers - CSG10, CSG01, CSG30 series,**  
each chip includes 1 rectangular spring,  
typical curvature radius is 6 nm, Au reflective coating \*

P/N	ITEM	PRICE, Euro
CSG10W, CSG01W, CSG30W	Nonseparated wafer, minimum 410 chips	4080
CSG10/400, CSG01/400, CSG30/400	400 separated chips	4420
CSG10/300, CSG01/300, CSG30/300	300 separated chips	3570
CSG10/200, CSG01/200, CSG30/200	200 separated chips	2550
CSG10/100, CSG01/100, CSG30/100	100 separated chips	1360
CSG10/50, CSG01/50, CSG30/50	50 separated chips	850
CSG10/15, CSG01/15, CSG30/15	15 separated chips	300

\* - for ordering cantilevers without reflective coating, please, add 'bare' after series name as it's in example: **NSG01/bare/15**  
The price is the same as for cantilevers with Au reflective coating.

**TIPLESS contact and noncontact "Golden" silicon cantilevers,**  
CSG01, CSG10, CSG30, NSG01, NSG10, NSG03, NSG30, FMG01 series  
Au reflective coating

P/N	ITEM	PRICE, Euro
CSG01/tipless, CSG10/tipless, CSG30/tipless, NSG01/tipless, NSG10/tipless, NSG03/tipless, NSG30/tipless, FMG01/tipless	Nonseparated wafer, minimum 410 chips	4080
	400 separated chips	4420
	300 separated chips	3570
	200 separated chips	2550

**CONDUCTIVE contact and noncontact "Golden" silicon cantilevers,**  
CSG01, CSG10, CSG30, NSG01, NSG10, NSG03, NSG30, FMG01 series  
with TiN, Au, Pt conductive coatings,  
thickness of conductive coatings is 20-30nm

P/N	ITEM	PRICE, Euro
CSG01/Pt, TiN, Au, CSG30/Pt, NSG01/Pt, TiN, Au NSG10/Pt, TiN, Au NSG03/Pt, TiN, Au NSG30/Pt, TiN, Au FMG01/Pt, TiN, Au	Nonseparated wafer, minimum 410 chips	4560
	400 separated chips	4940
	300 separated chips	3990
	200 separated chips	2850
	100 separated chips	1520
	50 separated chips	950
	15 separated chips	360

**DIAMOND LIKE CONDUCTIVE** "Golden" silicon cantilevers,  
cantilevers DCP11 series with diamond coating,  
thickness of the coating is 50-70 nm

P/N	ITEM	PRICE, Euro
DCP11/50, DCP20/50	50 separated chips	1250
DCP11/15, DCP20/15	15 separated chips	450

**MAGNETIC** "Golden" silicon cantilevers,  
cantilevers NSG01, FMG01 series with Co/Cr magnetic coatings,  
thickness of the coating is 30-40 nm

P/N	ITEM	PRICE, Euro
NSG01/Co/50, FMG01/Co/50	50 separated chips	1370
NSG01/Co/15, FMG01/Co/15	15 separated chips	480

**SUPER SHARP Diamond-Like Carbon (DLC) tips**  
typical curvature radius 1-3nm, grown on the cantilevers NSG01, NSG10 series  
(by request can be grown on other silicon cantilever series)

P/N	ITEM	PRICE, Euro
NSG01_DLC/50, NSG10_DLC/50	50 separated chips	2500
NSG01_DLC/10, NSG10_DLC/10	10 separated chips	600

**CONTACT and NONCONTACT "Whisker type" silicon cantilevers**  
NSC05, CSC05 series  
(each chip includes 1 rectangular spring, angle at the top less than 10 degrees,  
typical curvature radius less than 10 nm, Au reflective coating)

P/N	ITEM	PRICE, Euro
NSC05/15, CSC05/15	15 separated chips	1000
NSC05/10, CSC05/10	10 separated chips	750
NSC05/5, CSC05/5	5 separated chips	400

#### COLLOIDAL PROBES

- with submicron spheres attached to silicon tip, sphere type - SiO<sub>2</sub>, sphere size - 270/650/900nm

P/N	ITEM	PRICE, Euro
CSG30_Bio270/Au/5 CSG30_Bio650/Au/5 CSG30_Bio900/Au/5 FMG01_Bio270/Au/5 FMG01_Bio650/Au/5 FMG01_Bio900/Au/5 NSG01_Bio270/Au/5 NSG01_Bio650/Au/5 NSG01_Bio900/Au/5	5 separated chips	550

- with micron spheres attached to tipless probes, sphere type - Au / SiO<sub>2</sub> / BSG/ PS, sphere size from 5 to 20um

P/N	ITEM	PRICE, Euro
CPC_SiO2-A/Au/5 CPC_Au-A/Au/5 CPFM_Au-A/Au/5 CPFM_SiO2-A/Au/5 CPN_Au-A/Au/5 CPN_SiO2-A/Au/5	5 separated chips	650

#### Probes for Nanoeducator

P/N	ITEM	PRICE, Euro
WT105Ed	Set of 7 probes for NanoEducator	840

#### AFM probes for Nanoindenter

P/N	ITEM	PRICE, Euro
NSP01_NTF	1 probe for Nanoindenter (soft type)	1450
NSP10_NTF	1 probe for Nanoindenter (hard type)	1450
CO_QTZ	1 test sample for Nanoindenter	190

purchasing 2 Nanoindenter probes, the sample is for free!!!

#### NEW!!! Scanning Thermal probes

P/N	ITEM	PRICE, Euro
SThM_P/5	5 Probes for Scanning Thermal Microscopy	1590

#### Substrates

P/N	ITEM	PRICE, Euro
SU001	Set of 10 substrates of polycrystalline sapphire	239
SU002	Substrate of polycrystalline sapphire with holder for large samples up to 40x40mm.	40
SU015	Universal sample holder with contact spring for STM and Spreading Resistance modes.	82
Mica/15x15	Mica, Squares, 0.15 mm (0.006") thickness, size 15 mm x 15 mm (Pkg of 20)	275
Mica/dia.9,5	Mica, Disks, 0.15 mm (0.006") thickness, size 9.5 mm diameter (Pkg of 20)	320
MD001	10 steel sample holders (dia.10mm, thickness 0,5mm)	35

#### STM accessories

P/N	ITEM	PRICE, Euro
WTSTM1	Toolkit for STM (scissors, tweezers, 10 cm of Pt-Ir wire)	143
SHP01Ed	Special probe etching device	746
STM/Pt_10	Pt-Ir 80/20 wire, dia. 0,5mm, 10cm	60
STM/W_50	Tungsten wire, dia. 0,15mm, 50cm	10
SU015	Universal sample holder with contact spring for STM and Spreading Resistance modes.	82
TDG01/Au	Diffraction grating for submicron calibration SPM in the X or Y direction, Au reflective coating, period 278nm	300

#### Calibration gratings and Test samples

P/N	ITEM	PRICE, Euro
DNA01	Linear DNA molecules (3000 b. p.) deposited onto freshly cleaved mica. Molecule density - 0,5-7 molec./um <sup>2</sup>	150

TDG01	Diffraction grating for submicron calibration SPM in the X or Y direction, period 278nm	200
SNG01	Test grating for Scanning Near field Optical Microscope	200
TGZ1	Linear silicon gratings for Z calibration (height: TGZ1 - 19±1 nm)	100
TGZ2	Linear silicon gratings for Z calibration (height: TGZ2 - 104±1,5 nm)	100
TGZ3	Linear silicon gratings for Z calibration (height: TGZ3 - 540±2 nm)	100
TGZ4	Linear silicon gratings for Z calibration (height: TGZ3 - 1317±8 nm)	100
TGG1	Silicon triangular grating	200
TGT1	Silicon tip grating	300
TGX1	Silicon square grating with negative angles	200
TGS1	Set of 3 linear silicon gratings for Z calibration (3 different heights: TGZ1 - 19±1 nm, TGZ2 - 104±1,5nm, TGZ3 - 540±2 nm);	200
TGS2	Microscope grating set (TGG1, TGX1, TGT1, TGS1)	500
TGQ1	Silicon square grating for simultaneous calibration in X,Y and Z direction	300
TGSFull	Microscope grating set (TGG1, TGX1, TGT1, TGS1, TGQ1, TDG01)	850
STEPP	Silicon calibration sample with naturally step height 3,14nm.	100
SIC/1,5	Test sample for calibrating AFM scanner movements along the Z axis with step height 1,5nm	120
SIC/0,75	Test sample for calibrating AFM scanner movements along the Z axis with step height 0,75nm	120
PFM03	Test pattern for Piezoresponce Force Microscopy	350

**(HOPG) Highly Oriented Pyrolytic Graphite / Size each 10x10 mm<sup>2</sup>**  
 Pieces with other sizes are available:  
 for ZYA and ZYB quality till 12x12mm<sup>2</sup>, for ZYH quality till 30x30mm<sup>2</sup>.

P/N	ITEM	PRICE, Euro
<b>Mosaic Spread: 0.4 +/- 0.1 degree (ZYA Quality)</b>		
GRAS/1,5	Nominal thickness 1,5	137.5
GRAS/1,2	Nominal thickness 1,2±0,2	106.25
<b>Mosaic Spread: 0.8 +/- 0.2 degree (ZYB Quality)</b>		
GRBS/2,0	Nominal thickness 2,0	62.5
GRBS/1,7	Nominal thickness 1,7±0,2	52.5
GRBS/1,2	Nominal thickness 1,2±0,2	37.5
GRBS/0,6	Nominal thickness 0,6±0,1	20

**SNOM probes**

P/N	ITEM	PRICE, Euro
MF001	SNOM probes (10 probes, aperture: less than 100nm, fiber diameter 125um, probe length 2m, probe tip coated by Al - 7-8mm, transmitted wavelength 400-550 nm).	1190
MF002	SNOM probes (10 probes, aperture: less than 100nm, fiber diameter 125um, probe length 2m, probe tip coated by Al - 7-8mm, transmitted wavelength 450-600 nm).	1190
MF003	SNOM probes (10 probes, aperture: less than 100nm, fiber diameter 125um, probe length 2m, probe tip coated by Al - 7-8mm, transmitted wavelength 600-770 nm).	1190
MF004	SNOM probes (10 probes, aperture: less than 100nm, fiber diameter 125um, probe length 2m, probe tip coated by Al - 7-8mm, transmitted wavelength 780-970 nm).	1190
MF005	SNOM probes (10 probes, aperture: less than 100nm, fiber diameter 125um, probe length 2m, probe tip coated by Al - 7-8mm, transmitted wavelength 980-1600 nm).	1190
MF012	SNOM probes with glued quartz tuning-forks for Solver line systems with measuring heads SNC100, SNC080, SNLG100, SNLG080 (10 probes, aperture: less than 100nm, fiber diameter 125 um, probe length 2m, probe tip coated by Al - 7-8mm, transmitted wavelength 450-600 nm).	2500
MF013	SNOM probes with glued quartz tuning-forks for Solver line systems with measuring heads SNC100, SNC080, SNLG100, SNLG080 (10 probes, aperture: less than 100nm, fiber diameter 125um, probe length 2m, probe tip coated by Al - 7-8mm, transmitted wavelength 600-770 nm).	2500
MF014	SNOM probes with glued quartz tuning-forks for Solver line systems with measuring heads SNC100, SNC080, SNLG100, SNLG080 (10 probes, aperture: less than 100nm, fiber diameter 125um, probe length 2m, probe tip coated by Al - 7-8mm, transmitted wavelength 780-970 nm).	2500
MF012_NTF	SNOM probes with glued quartz tuning-fork for NTEGRA line systems with measuring head SNLG100NTF (10 probes, aperture: less than 100nm, fiber diameter 125um, probe length 2m, probe tip coated by Al - 7-8mm, transmitted wavelength 450-600 nm).	2500
MF013_NTF	SNOM probes with glued quartz tuning-forks for NTEGRA line systems with measuring head SNLG100NTF (10 probes, aperture: less than 100nm, fiber diameter 125um, probe length 2m, probe tip coated by Al - 7-8mm, transmitted wavelength 600-770nm).	2500
MF014_NTF	SNOM probes with glued quartz tuning-forks for NTEGRA line systems with measuring head SNLG100NTF (10 probes, aperture: less than 100nm, fiber diameter 125um, probe length 2m, probe tip coated by Al - 7-8mm, transmitted wavelength 780-970 nm).	2500
MF111_NTF	SNOM probes with glued quartz tuning-forks for NTEGRA line systems with measuring head SNLG101NTF and Solver line systems with measuring head SNLG101 (10 probes, aperture: less than 100nm, fiber diameter 125um, probe length 2m, probe tip coated by Al - 7-8mm, transmitted wavelength 400-550 nm).	2500
MF112_NTF	SNOM probes with glued quartz tuning-forks for NTEGRA line systems with measuring head SNLG101NTF and Solver line systems with measuring head SNLG101 (10 probes, aperture: less than 100nm, fiber diameter 125um, probe length 2m, probe tip coated by Al - 7-8mm, transmitted wavelength 450-600 nm).	2500
MF113_NTF	SNOM probes with glued quartz tuning-forks for NTEGRA line systems with measuring head SNLG101NTF and Solver line systems with measuring head SNLG101 (10 probes, aperture: less than 100nm, fiber diameter 125um, probe length 2m, probe tip coated by Al - 7-8mm, transmitted wavelength 600-770 nm).	2500
MF114_NTF	SNOM probes with glued quartz tuning-forks for NTEGRA line systems with measuring head SNLG101NTF and Solver line systems with measuring head SNLG101 (10 probes, aperture: less than 100nm, fiber diameter 125um, probe length 2m, probe tip coated by Al - 7-8mm, transmitted wavelength 780-970 nm).	2500
MF115_NTF	SNOM probes with glued quartz tuning-forks for NTEGRA line systems with measuring head SNLG101NTF and Solver line systems with measuring head SNLG101 (10 probes, aperture: less than 100nm, fiber diameter 125um, probe length 2m, probe tip coated by Al - 7-8mm, transmitted wavelength 980-1600 nm).	2500

**Tuning forks for SNOM probes**

P/N	ITEM	PRICE, Euro
TF001/10	Set of 10 tuning forks for Solver line systems with measuring heads SNC100, SNC080, SNLG100, SNLG080 .	1000
TF001_NTF/10	Set of 10 tuning forks for NTEGRA line systems with measuring head SNLG100NTF.	1250
TF101_NTF/10	Set of 10 tuning forks for NTEGRA line systems with measuring head SNLG101NTF and Solver line systems with measuring head SNLG101.	1250

**Cantilever sets**

P/N	ITEM	PRICE, Euro
BIOSET-200	AFM probe sets: 50 chips - for contact AFM; 100 chips - for noncontact modes; 50 chips - contact AFM for liquid	3500
MSSET/200	AFM probe sets: 50 chips - for contact AFM; 100 chips - for noncontact modes; 20 chips - for spreading resistance; 25 chips - for SKM/SCM; 5 chips - for MFM	3075
POLYSET/160	AFM AFM probe sets: 50 chips - for contact AFM; 100 chips - for noncontact modes; 5 chips - for SRI/SKM/SCM; 5 chips - for MFM	2475
POLYSET/155	AFM probe sets: 50 chips - for contact AFM; 100 chips - for noncontact modes; 5 chips - for MFM	2400
SEMISSET/200	AFM probe sets: 50 chips - for contact AFM; 100 chips - for noncontact modes; 20 chips - for spreading resistance; 20 chips - for SKM/SCM; 5 chips - for MFM; 5 chips NSC05 "Whisker type" for deep trenches measurements	3400
BIOSET - 50	AFM probe sets: 10 chips - for contact AFM; 30 chips - noncontact modes; 10 chips - for contact AFM for liquid	1100
MSSET/50	AFM probe sets: 10 chips - for contact AFM; 25 chips - for noncontact modes; 5 chips - for spreading resistance; 5 chips - for SKM/SCM; 5 chips - for MFM	1050
POLYSET/50	AFM probe sets: 10 chips - for contact AFM; 30 chips - for noncontact modes; 5 chips - for SRI/SKM/SCM; 5 chips - for MFM	1050
POLYSET/45	AFM probe sets: 10 chips - for contact AFM; 30 chips - for noncontact modes; 5 chips - for MFM	950
SEMISSET/47	AFM probe sets: 10 chips - for contact AFM; 20 chips - for noncontact modes; 5 chips - for spreading resistance; 5 chips - for SKM/SCM; 5 chips - for MFM; 2 chips NSC05 "Whisker type" for deep trenches measurements	1210
HALF WAFERS		
CSG10W	Nonseparated wafer, minimum 410 chips	2420
CSG10/P/HW	Nonseparated wafer, minimum 410 chips	2700